

Search Notes**Application/Control No.**

10/670,562

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

FUJII ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	232	12/22/2006	EB
375	229	12/22/2006	EB
375	233	12/22/2006	EB
375	234	12/22/2006	EB
375	346	12/22/2006	EB
375	2348	12/22/2006	EB
375	350	12/22/2006	EB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	12/20/2006	EB
Plus	12/20/2006	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	232	12/22/2006	EB
375	346	12/22/2006	EB
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